

**SN5420, SN54LS20, SN54S20,
SN7420, SN74LS20, SN74S20**
DUAL 4-INPUT POSITIVE-NAND GATES
DECEMBER 1983—REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

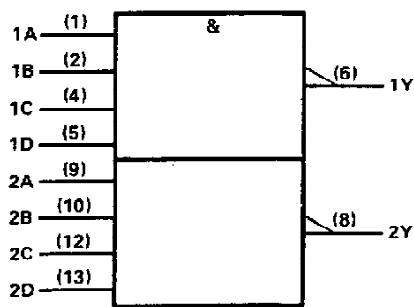
These devices contain two independent 4-input NAND gates.

The SN5420, SN54LS20, and SN54S20 are characterized for operation over the full military range of -55°C to 125°C. The SN7420, SN74LS20, and SN74S20 are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)

INPUTS				OUTPUT
A	B	C	D	Y
H	H	H	H	L
L	X	X	X	H
X	L	X	X	H
X	X	L	X	H
X	X	X	L	H

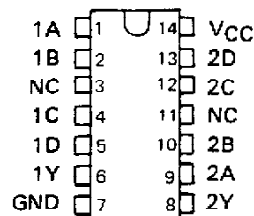
logic symbol†



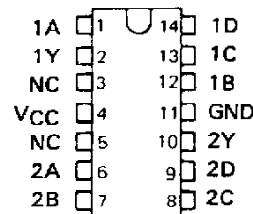
†This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

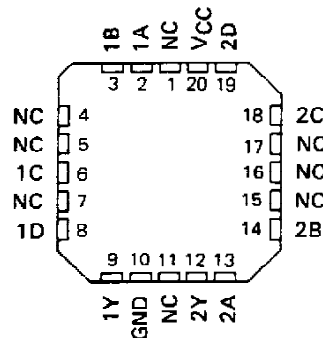
SN5420 . . . J PACKAGE
SN54LS20, SN54S20 . . . J OR W PACKAGE
SN7420 . . . N PACKAGE
SN74LS20, SN74S20 . . . D OR N PACKAGE
(TOP VIEW)



SN5420 . . . W PACKAGE
(TOP VIEW)

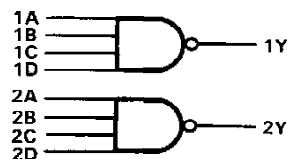


SN54LS20, SN54S20 . . . FK PACKAGE
(TOP VIEW)



NC - No internal connection

logic diagram



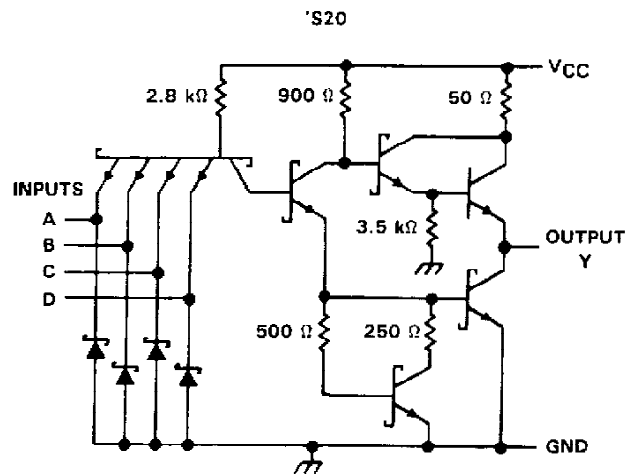
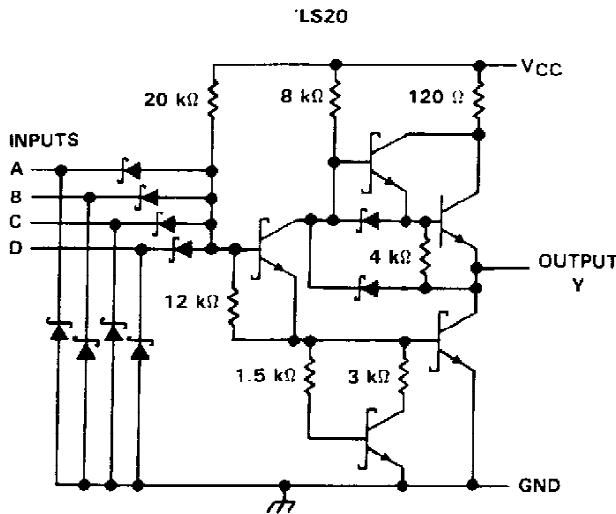
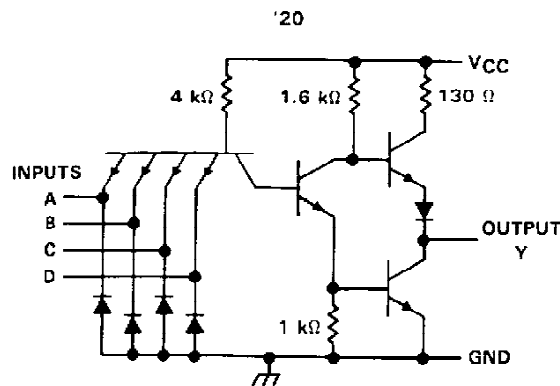
positive logic $Y = \overline{A \cdot B \cdot C \cdot D}$ or $Y = \overline{A} + \overline{B} + \overline{C} + \overline{D}$

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



**SN5420, SN54LS20, SN54S20,
SN7420, SN74LS20, SN74S20
DUAL 4-INPUT POSITIVE-NAND GATES**

schematics (each gate)



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage: '20, 'S20	5.5 V
'LS20	7 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminals.

SN5420, SN7420 DUAL 4-INPUT POSITIVE-NAND GATES

recommended operating conditions

	SN5420			SN7420			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.8			0.8	V
I _{OH} High-level output current			-0.4			-0.4	mA
I _{OL} Low-level output current			16			16	mA
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN5420			SN7420			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -12 mA			-1.5			-1.5	V
V _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, I _{OH} = -0.4 mA	2.4	3.4		2.4	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 16 mA		0.2	0.4		0.2	0.4	V
I _I	V _{CC} = MAX, V _I = 5.5 V			1			1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.4 V			40			40	μA
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-1.6			-1.6	mA
I _{OS} §	V _{CC} = MAX	-20		-55	-18		-55	mA
I _{CCH}	V _{CC} = MAX, V _I = 0 V		2	4		2	4	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V		6	11		6	11	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Any	Y	R _L = 400 Ω, C _L = 15 pF		12	22	ns
t _{PHL}					8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.


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SN54LS20, SN74LS20 DUAL 4-INPUT POSITIVE-NAND GATES

recommended operating conditions

	SN54LS20			SN74LS20			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.7			0.8	V
I _{OH} High-level output current			-0.4			-0.4	mA
I _{OL} Low-level output current			4			8	mA
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54LS20			SN74LS20			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -18 mA			-1.5			-1.5	V
V _{OH}	V _{CC} = MIN, V _{IL} = MAX, I _{OH} = -0.4 mA	2.5	3.4		2.7	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 4 mA		0.25	0.4			0.4	V
	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 8 mA				0.25	0.5		
I _I	V _{CC} = MAX, V _I = 7 V			0.1			0.1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			20			20	µA
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-0.4			-0.4	mA
I _{OS} §	V _{CC} = MAX	-20		-100	-20		-100	mA
I _{CCH}	V _{CC} = MAX, V _I = 0 V		0.4	0.8		0.4	0.8	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V		1.2	2.2		1.2	2.2	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Any	Y	R _L = 2 kΩ, C _L = 15 pF		9	15	ns
t _{PHL}					10	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.


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SN54S20, SN74S20 DUAL 4-INPUT POSITIVE-NAND GATES

recommended operating conditions

	SN54S20			SN74S20			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH} High-level input voltage	2			2			V
V_{IL} Low-level input voltage			0.8			0.8	V
I_{OH} High-level output current			-1			-1	mA
I_{OL} Low-level output current			20			20	mA
T_A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54S20			SN74S20			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V_{IK}	$V_{CC} = \text{MIN}$, $I_I = -18 \text{ mA}$			-1.2			-1.2	V
V_{OH}	$V_{CC} = \text{MIN}$, $V_{IL} = 0.8 \text{ V}$, $I_{OH} = -1 \text{ mA}$	2.5	3.4		2.7	3.4		V
V_{OL}	$V_{CC} = \text{MIN}$, $V_{IH} = 2 \text{ V}$, $I_{OL} = 20 \text{ mA}$			0.5			0.5	V
I_I	$V_{CC} = \text{MAX}$, $V_I = 5.5 \text{ V}$			1			1	mA
I_{IH}	$V_{CC} = \text{MAX}$, $V_I = 2.7 \text{ V}$			50			50	μA
I_{IL}	$V_{CC} = \text{MAX}$, $V_I = 0.5 \text{ V}$			-2			-2	mA
$I_{OS} §$	$V_{CC} = \text{MAX}$	-40		-100	-40		-100	mA
I_{CCH}	$V_{CC} = \text{MAX}$, $V_I = 0 \text{ V}$		5	8		5	8	mA
I_{CCL}	$V_{CC} = \text{MAX}$, $V_I = 4.5 \text{ V}$		10	18		10	18	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$.

§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
t_{PLH}	A, B, C or D	Y	$R_L = 280 \Omega$, $C_L = 15 \text{ pF}$		3	4.5	ns	
t_{PHL}					3	5	ns	
t_{PLH}			$R_L = 280 \Omega$, $C_L = 50 \text{ pF}$			4.5		ns
t_{PHL}						5		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.


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